

IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100µm chip
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- IGBT Modules
- Applications:
- drives



Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC25T60NC	600V	30A	4.5 x 5.71 mm ²	sawn on foil	Q67050-A4143- A001

MECHANICAL PARAMETER:

Raster size	4.5 x 5.71			
Area total / active	25.69 / 21.4			
Emitter pad size	2x(2.18x1.58)			
Gate pad size	0.68 x 1.08			
Thickness	100	μm		
Wafer size	150	mm		
Flat position	270	deg		
Max.possible chips per wafer	566			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm Al Si 1%			
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500µm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	90	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I _C =1000µA	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =30A	1.7	2.0	2.5	V
Gate-emitter threshold voltage	V _{GE(th)}	I_C =700µA, V_{GE} = V_{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V			2.1	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V, V_{GE} =20V			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Input capacitance	Ciss	V _{CE} =25V	-	1350		pF
Output capacitance	Coss	$V_{GE}=0V$	-	tbd		
Reverse transfer capacitance	Crss	f=1MHz	-	120		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions ¹⁾	Value			Unit
			min.	typ.	max.	
Turn-on delay time	t _{d(on)}	<i>T</i> _j =125°C V _{CC} =300V	-	21		ns
Rise time	t _r	/c=30A	-	8		
Turn-off delay time	$t_{d(off)}$	$V_{GE}=\pm 15V$ $R_{G}=8.2\Omega$	-	110		
Fall time	t _f		-	25		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:



Edited by INFINEON Technologies AI PS DD HV3, L 7262-M, Edition 2, 28.11.2003



FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

FS 30 R06 XL4

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG, Bereich Kommunikation St.-Martin-Strasse 53, D-81541 München © Infineon Technologies AG 2002 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.